

Power MOSFET

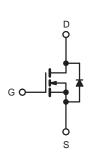
PRODUCT SUMMARY					
V _{DS} (V)	850				
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	2.40			
Q _g (Max.) (nC)	28				
Q _{gs} (nC)	5				
Q _{gd} (nC)	12				
Configuration	Single				

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C	= 25 °C, unl	ess otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V _{DS}	850	V
Gate-Source Voltage			V _{GS}	± 20	v
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	la la	5.5	
Continuous Drain Ourrent	VGS at 10 V	T _C = 100 °C	۱ _D	3.9	A
Pulsed Drain Current ^a	rain Current ^a		I _{DM}	24	
Linear Derating Factor				1.5	W/°C
Single Pulse Avalanche Energy ^b			E _{AS}	770	mJ
Repetitive Avalanche Current ^a		I _{AR}	7.8	A	
Repetitive Avalanche Energy ^a			E _{AR}	19	mJ
Maximum Power Dissipation	T _C = 25 °C		P _D 45		W
Peak Diode Recovery dV/dt ^c			dV/dt	5.0	V/ns
erating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for	10 s		300 ^d	
Mounting Torque	6-32 or M3 screw			10	lbf ∙ in
Mounting Torque			Γ	1.1	N · m

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 50$ V, starting $T_J = 25$ °C, L = 23 mH, $R_g = 25 \Omega$, $I_{AS} = 7.8$ A (see fig. 12). c. $I_{SD} \le 7.8$ A, dl/dt ≤ 140 A/µs, $V_{DD} \le 600$ V, $T_J \le 150$ °C. d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

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THERMAL RESISTANCE RATI	NGS								
PARAMETER	SYMBOL	TYP.		MAX.			UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-		40					
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24		-			°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-		0.65					
SPECIFICATIONS (T _J = 25 °C, u	nless otherwi	se noted)			1	1	1	T	
PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT	
Static		1				•	•	T	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0 V, I _D =	250 µA	850	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	$I_D = 1 \text{ mA}$	-	0.98	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	$= V_{GS}, I_D =$	250 µA	2.0	-	4.0	V	
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20$	V	-	-	± 100	nA	
Zero Gate Voltage Drain Current	laas	V _{DS} =	= 850 V, V _C	_{as} = 0 V	-	-	1	μA	
Zero Gate Voltage Drain Gurrent	IDSS	V _{DS} = 680 \	V, V _{GS} = 0 V	∕, T _J = 125 °C	-	-	45	μΑ	
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$	ار	_b = 3.7 A ^b	-	2.40	-	Ω	
Forward Transconductance	g fs	V _{DS} =	= 100 V, I _D :	= 3.7 A ^b	4.5	-	-	S	
Dynamic									
Input Capacitance	C _{iss}		V _{GS} = 0 \	1	-	816	-		
Output Capacitance	C _{oss}	$V_{DS} = 25 V,$		-	68	-	pF		
Reverse Transfer Capacitance	C _{rss}	f = 1	f = 1.0 MHz, see fig. 5		-	17	-	1	
Total Gate Charge	Qg		I _D = 3.8 A, V _{DS} = 400 V, see fig. 6 and 13 ^b	-	-	28	nC		
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	5			
Gate-Drain Charge	Q _{gd}		3001	ig. o and to	-	-	12	-	
Turn-On Delay Time	t _{d(on)}		•		-	15	-		
Rise Time	t _r		= 400 V, I _D		-	27	-		
Turn-Off Delay Time	t _{d(off)}	R _g =	$R_{g} = 6.2 \Omega, R_{D} = 52 \Omega$ see fig. 10 ^b - 66		66	-	- ns		
Fall Time	t _f				30	-			
Internal Drain Inductance	L _D	Between lead 6 mm (0.25") t			-	5.0	-		
Internal Source Inductance	L _S	package and die contact	package and center of die contact	13	-	- nH			
Drain-Source Body Diode Characteristic	s	•				•	•	•	
Continuous Source-Drain Diode Current	I _S	MOSFET sym showing the	ibol		-	-	5.0	^	
Pulsed Diode Forward Current ^a	I _{SM}	integral revers p - n junction			-	-	21	A	
Body Diode Voltage	V _{SD}	$T_{J} = 25 \text{ °C}, I_{S} = 3.8 \text{ A}, V_{GS} = 0 \text{ V}^{b}$		-	-	1.8	V		
Body Diode Reverse Recovery Time	t _{rr}	$T_{J} = 25 \text{ °C}, I_{F} = 3.8 \text{ A}, \\ dl/dt = 100 \text{ A}/\mu\text{s}^{b}$		-	320		ns		
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.3		μC		
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time	is negligible (turn	-on is do	ninated k	vleand	· ·	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.



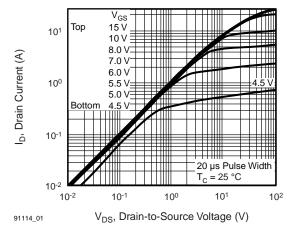


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

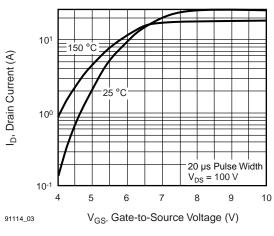


Fig. 3 - Typical Transfer Characteristics

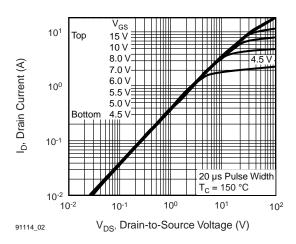


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

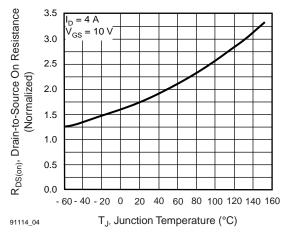


Fig. 4 - Normalized On-Resistance vs. Temperature



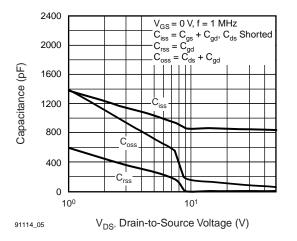


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

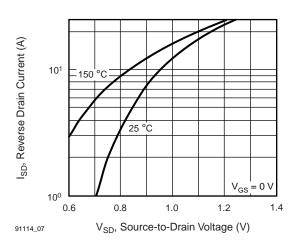


Fig. 7 - Typical Source-Drain Diode Forward Voltage

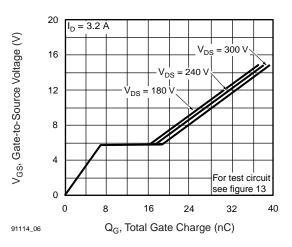


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

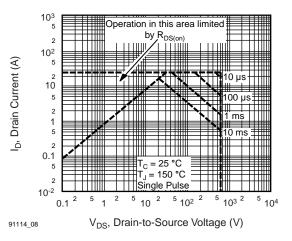


Fig. 8 - Maximum Safe Operating Area

SPA02N80C3



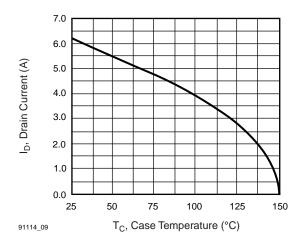


Fig. 9 - Maximum Drain Current vs. Case Temperature

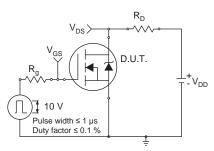


Fig. 10a - Switching Time Test Circuit

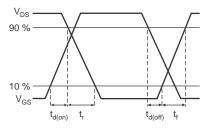


Fig. 10b - Switching Time Waveforms

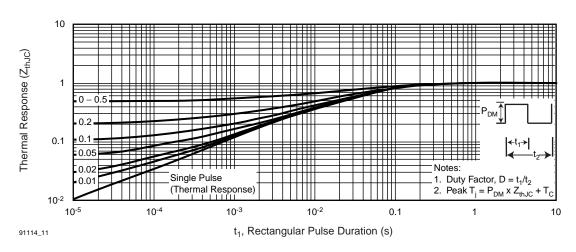


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

SPA02N80C3



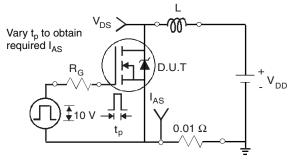


Fig. 12a - Unclamped Inductive Test Circuit

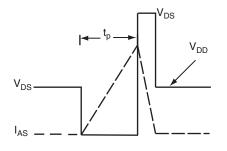


Fig. 12b - Unclamped Inductive Waveforms

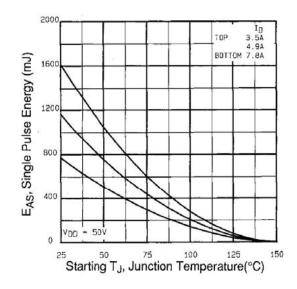


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

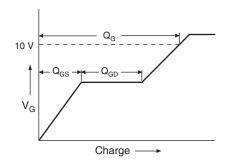


Fig. 13a - Basic Gate Charge Waveform

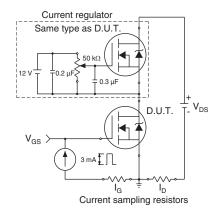
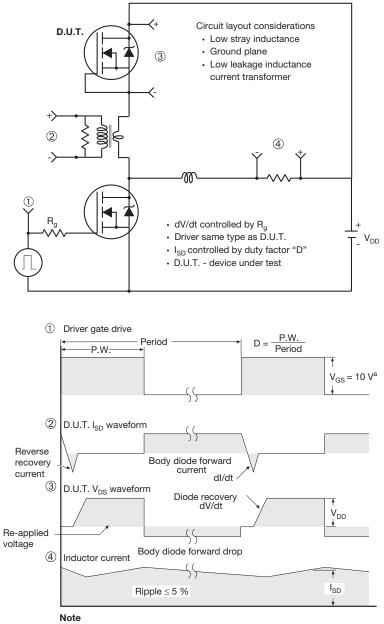


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

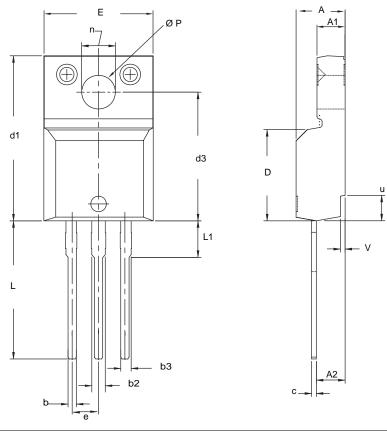


a. $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)



MAX.
0.190
0.111
0.112
0.035
0.055
0.055
0.025
0.386
0.635
0.509
0.419
0.100 BSC
0.541
0.138
0.242
0.136
0.098
0.020
2 8 0 4 6

Notes

1. To be used only for process drawing. 2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads. 3. All critical dimensions should C meet $C_{pk} > 1.33$. 4. All dimensions include burrs and plating thickness. 5. No chipping or package damage.



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